

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/646,470	CHIEN ET AL.	
Examiner	Art Unit	
Nashaat T. Nashed, Ph. D.	1656	

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
WEST Search	5/11/2007	NASH